MOSFET - Power

650 V, 150 m Ω , 24 A, Single N–Channel, D2PAK

Description

SUPERFET® III MOSFET is ON Semiconductor's brand-new high voltage super-junction (SJ) MOSFET family that is utilizing charge balance technology for outstanding low on-resistance and lower gate charge performance. This advanced technology is tailored to minimize conduction loss, provide superior switching performance, and withstand extreme dv/dt rate.

Consequently, SUPERFET III MOSFET is very suitable for the various power system for miniaturization and higher efficiency. SUPERFET III FRFET® MOSFET's optimized reverse recovery performance of body diode can remove additional component and improve system reliability.

Features

- 700 V @ $T_J = 150$ °C
- Typ. $R_{DS(on)} = 114 \text{ m}\Omega$
- Ultra Low Gate Charge (Typ. Q_g = 43 nC)
- Low Effective Output Capacitance (Typ. Coss(eff.) = 385 pF)
- 100% Avalanche Tested
- Qualified with AEC-Q101
- These Devices are Pb-Free and are RoHS Compliant

Typical Applications

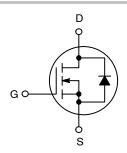
- Automotive On Board Charger
- Automotive DC/DC Converter for HEV



ON Semiconductor®

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V _{(BR)DSS}	R _{DS(ON)} MAX	I _D MAX
650 V	150 mΩ @ 10 V	24 A

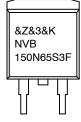


N-CHANNEL MOSFET



D²PAK-3 TO-263 CASE 418AJ

MARKING DIAGRAM



&Z = Assembly Plant Code &3 = Data Code (Year & Week)

&K = Lot

NVB150N65S3F = Specific Device Code

ORDERING INFORMATION

See detailed ordering and shipping information on page 8 of this data sheet.

Table 1. ABSOLUTE MAXIMUM RATINGS (T_C = 25°C unless otherwise stated)

Symbol	Parameter	Value	Unit		
V _{DSS}	Drain-to-Source Voltage	650			
V _{GS}	Gate-to-Source Voltage	- DC	±30	V	
		– AC (f > 1 Hz)	±30		
I _D	Drain Current	– Continuous (T _C = 25°C)	24	Α	
		– Continuous (T _C = 100°C)	15.2	1	
I _{DM}	Drain Current	Current – Pulsed (Note 1)		Α	
E _{AS}	Single Pulse Avalanche Energy (Note 2)		275	mJ	
I _{AS}	Avalanche Current		3.2	Α	
E _{AR}	Repeated Avalanche Energy (Note 1)		1.92	mJ	
dv/dt	MOSFET dv/dt		100	V/ns	
	Peak Diode Recovery dv/dt (Note 3)		50	1	
P _D	Power Dissipation	Tc = 25°C	192	W	
		- Derate Above 25°C	1.54	W/°C	
T _J , T _{stg}	Operating Junction and Storage Temperature		-55 to 150	°C	
TL	Maximum Lead Temperature for Soldering, 1/8" from Case for 5 Seconds		300	°C	

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

1. Repetitive rating: pulse – width limited by maximum junction temperature.

2. IAS = 3.2 A, RG = 25 Ω , starting T_J = 25°C.

3. ISD \leq 12 A, di/dt \leq 200 A/_s, V_{DD} \leq 400 V, starting T_C = 25°C.

Table 2. THERMAL RESISTANCE RATINGS

Symbol	Parameter	Max	Unit
$R_{ heta JC}$	Thermal Resistance, Junction-to-Case, Max.	0.65	°C/W
$R_{ heta JA}$	Thermal Resistance, Junction-to-Ambient, Max.	40	

ELECTRICAL CHARACTERISTICS (T_C = 25°C unless otherwise noted)

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
OFF CHARAC	TERISTICS					
BV _{DSS}	Drain-to-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 1 \text{ mA}, T_J = 25^{\circ}\text{C}$	650	-	_	V
		V _{GS} = 0 V, I _D = 10 mA, T _J = 150°C	700	_	-	V
$\Delta BV_{DSS}/\Delta T_{J}$	Breakdown Voltage Temperature Coefficient	I _D = 20 mA, Referenced to 25°C	-	0.61	_	V/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 650 V, V _{DS} = 0 V	i	-	10	μΑ
		V _{DS} = 520 V, T _C = 125°C	i	128	-	μΑ
I _{GSS}	Gate-to-Body Leakage Current	$V_{GS} = 0 \text{ V}, I_D = 1 \text{ mA}, T_J = 25^{\circ}\text{C}$	-	-	±100	nA
ON CHARACT	FERISTICS				•	
V _{GS(th)}	Drain-to-Source Breakdown Voltage	$V_{GS} = V_{DS}, I_D = 0.54 \text{ mA}$	3.0	-	5.0	V
R _{DS(on)}	Static Drain-to-Source On Resistance	V _{GS} = 10 V, I _D = 12 A	-	114	150	mΩ
9FS	Forward Transconductance	V _{GS} = 20 V, I _D = 12 A	-	14	_	S
DYNAMIC CH	ARACTERISTICS				•	•
C _{iss}	Input Capacitance	V _{DS} = 400 V, V _{GS} = 0 V, f = 1 MHz	-	1999	-	pF
C _{oss}	Output Capacitance		_	40.1	_	pF
C _{oss(eff.)}	Effective Output Capacitance	V _{DS} = 0 to 400 V, V _{GS} = 0 V	-	385	_	pF
C _{oss(er.)}	Energy Related Output Capacitance	V _{DS} = 0 to 400 V, V _{GS} = 0 V	i	72	-	pF
Q _{g(total)}	Total Gate Charge at 10 V	V _{DS} = 400 V, I _D = 12 A, V _{GS} = 10 V (Note 4)	-	43	-	nC
Q _{gs}	Gate-to-Source Gate Charge		-	13	-	nC
Q _{gd}	Gate-to-Drain "Miller" Charge		-	17	-	nC
ESR	Equivalent Series Resistance	F = 1 MHz	-	5	-	Ω
SWITCHING C	CHARACTERISTICS, V _{GS} = 10 V				•	•
t _{d(on)}	Turn-On Delay Time	$V_{DD} = 400 \text{ V}, I_D = 12 \text{ A},$	-	21	_	ns
t _r	Rise Time	$V_{GS} = 10 \text{ V}, R_{G} = 4.7 \Omega$ (Note 4)	i	13	-	ns
t _{d(off)}	Turn-Off Delay Time		-	53	-	ns
t _f	Fall Time		i	3	-	ns
SOURCE-DRA	AIN DIODE CHARACTERISTICS					
Is	Maximum Continuous Source-to-Drain Diode Forward Current		-	-	24	Α
I _{SM}	Maximum Pulsed Source-to-Drain Diode Forward Current		-	-	60	Α
V _{SD}	Source-to-Drain Diode Forward Voltage	V _{GS} = 0 V, I _{SD} = 12 A	-	-	1.3	V
t _{rr}	Reverse-Recovery Time	V _{GS} = 0 V, I _{SD} = 12 A,	-	88	-	ns
Q_{rr}	Reverse-Recovery Charge	dI _F /dt = 100 A/μs	-	300	-	nC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

4. Essentially independent of operating temperature typical characteristics.

TYPICAL CHARACTERISTICS

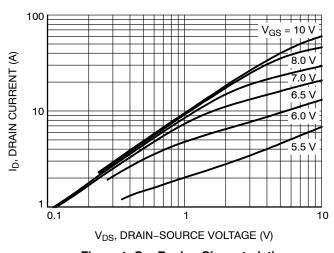


Figure 1. On-Region Characteristics 25°C

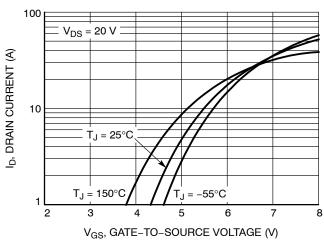


Figure 3. Transfer Characteristics

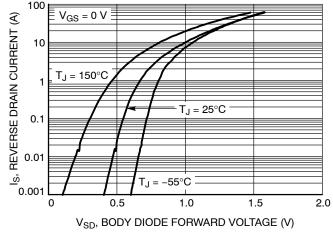


Figure 5. Body Diode Forward Voltage Variation vs. Source Current and Temperature

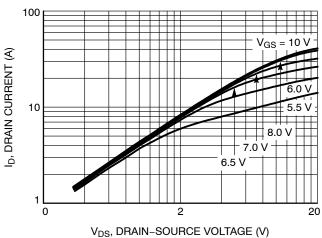


Figure 2. On-Region Characteristics 150°C

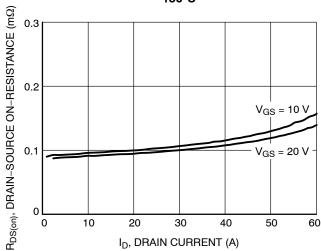


Figure 4. On-Resistance Variation vs. Drain **Current and Gate Voltage**

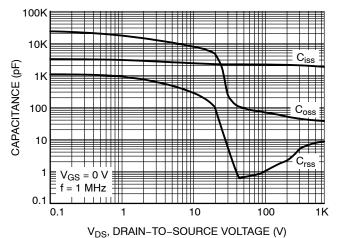


Figure 6. Capacitance Characteristics

TYPICAL CHARACTERISTICS

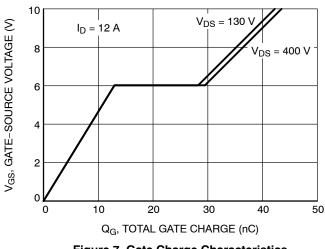


Figure 7. Gate Charge Characteristics

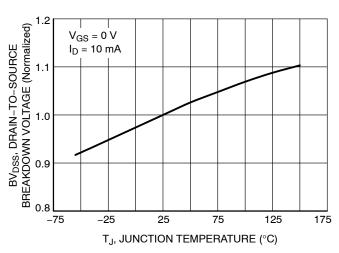


Figure 8. Breakdown Voltage Variation vs.
Temperature

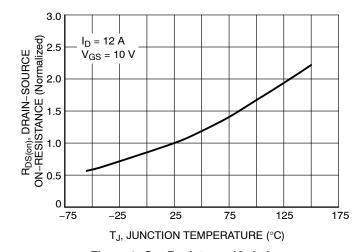


Figure 9. On–Resistance Variation vs.
Temperature

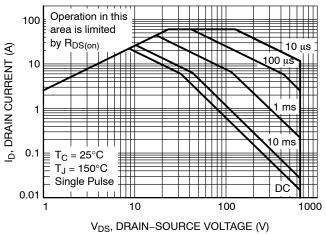


Figure 10. Maximum Safe Operating Area

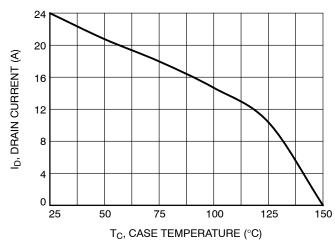


Figure 11. Maximum Drain Current vs. Case Temperature

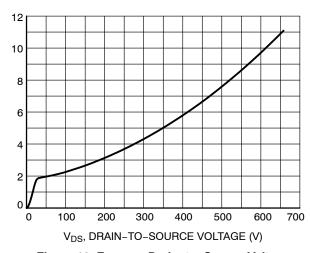
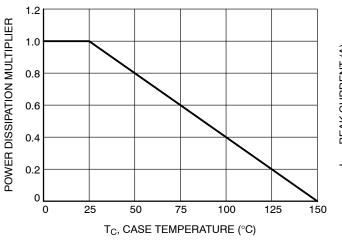


Figure 12. E_{OSS} vs. Drain-to-Source Voltage

Eoss (MJ)

TYPICAL CHARACTERISTICS

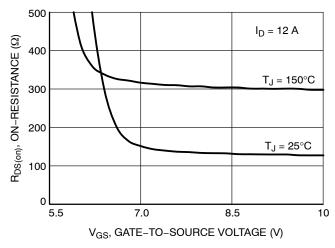


1000 (V) 100 Current Limited Max 1000001 0.0001 0.001 0.01 1 1 t, RECTANGULAR PULSE (s)

Figure 13. Normalized Power Dissipation vs.

Case Temperature

Figure 14. Peak Current Capability



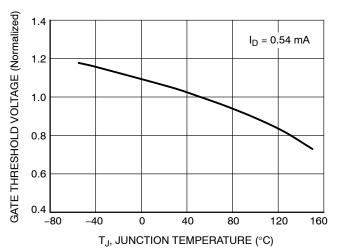


Figure 15. R_{DS(on)} vs. Gate Voltage

Figure 16. Normalized Gate Threshold Voltage vs. Temperature

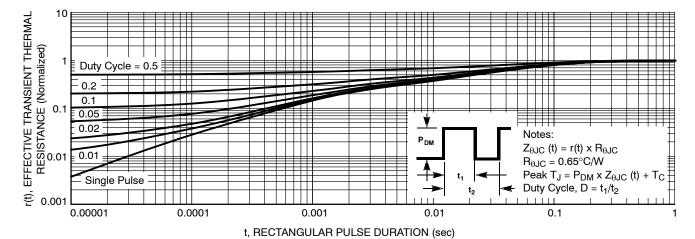


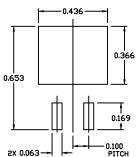
Figure 17. Transient Thermal Response

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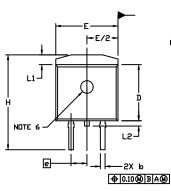
RECOMMENDED MOUNTING FOOTPRINT

For additional information on our Pb-Free strategy and soldering details, please download the DN Semiconductor Soldering and Mounting Table Semiconductor Manual Table 17 PROBLED

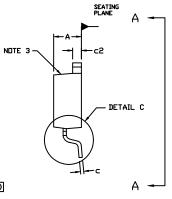
NOTES

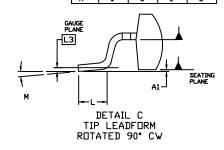
- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 2009.
- 2. CONTROLLING DIMENSION: INCHES
- 3. CHAMFER OPTIONAL.
- 4. DIMENSIONS D AND E DO NOT INCLUDE MOLD FLASH. MOLD FLASH SHALL NOT EXCEED 0.005 PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY AT DATUM H.
- 5. THERMAL PAD CONTOUR IS OPTIONAL WITHIN DIMENSIONS E, L1, D1, AND E1.
- 6. OPTIONAL MOLD FEATURE.
- 7. ①,② ... DPTIONAL CONSTRUCTION FEATURE CALL DUTS.

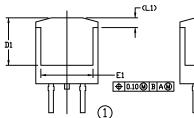
	INCHES		MILLIN	ETERS
DIM	MIN.	MAX.	MIN.	MAX.
A	0.160	0.190	4.06	4.83
A1	0.000	0.010	0.00	0.25
b	0.020	0.039	0.51	0.99
С	0.012	0.029	0.30	0.74
c2	0.045	0.065	1.14	1.65
D	0.330	0.380	8.38	9.65
D1	0.260		6.60	
E	0.380	0.420	9.65	10.67
E1	0.245		6.22	
e	0.100 BSC		2.54 BSC	
Н	0.575	0.625	14.60	15.88
L	0.070	0.110	1.78	2.79
L1		0.066		1.68
L2		0.070		1.78
L3	0.010	0.010 BSC 0.25 BSC		BSC
м	U+	8*	n•	8.

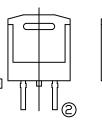


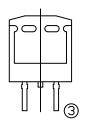
VIEW A-A

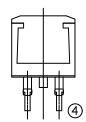








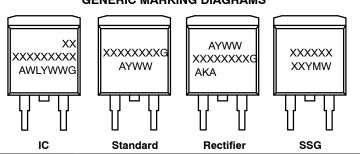




VIEW A-A

OPTIONAL CONSTRUCTIONS

GENERIC MARKING DIAGRAMS*



XXXXXX = Specific Device Code A = Assembly Location

WL = Wafer Lot
Y = Year
WW = Work Week
W = Week Code (SSG)
M = Month Code (SSG)
G = Pb-Free Package
AKA = Polarity Indicator

*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot " •", may or may not be present. Some products may not follow the Generic Marking.

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